

Search Notes

Application/Control No.

10/776,286

Examiner

Leith A. Al-Nazer

Applicant(s)/Patent under
Reexamination

ONOZAWA ET AL.

Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
315	169.1- 169.4	2/22/2006	LA
345	55, 60	2/22/2006	LA
345	204	2/22/2006	LA

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
315	169.3	2/22/2006	LA
315	169.4	2/22/2006	LA
345	55, 60	2/22/2006	LA
345/204		2/22/2006	LA

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST prior art text search (see "Examiner Search Notes")	2/22/2006	LA
EAST interference text search (see "Examiner Search Notes")	2/22/2006	LA